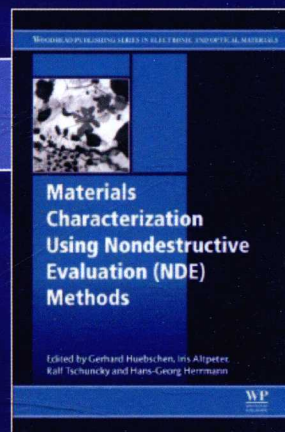


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Using Nondestructive Evaluation (NDE) Methods

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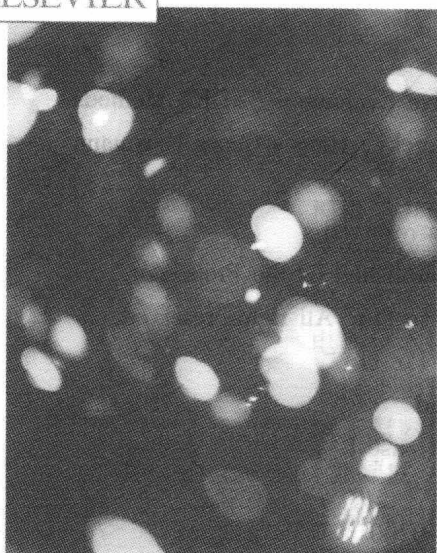
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Edited by Gerhard Hübschen, Iris Altpeter,
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内容简介

本书概述了能对材料进行长期、短期监测、评估和表征的无损检测方法(NDE)，主要包括材料表征的原子力显微术，扫描电子显微术，透射电子显微术，X射线显微术，X射线衍射技术，微波、毫米波和太赫兹波(MMT)技术，声学显微术，超声波技术，电磁技术以及混合技术。

本书内容切合实际，每一章重点介绍了不同的NDE技术，强调了材料的微观结构性质(如相含量和晶粒尺寸)，以及机械性能(如硬度、韧性、屈服强度、织构和残余应力)的测定方法。

本书可供土木、结构和机械工程师，材料学家，开发表征技术的物理学家以及汽车、航空航天和发电行业的研发人员使用。同时，本书也可作为高等院校材料、冶金、航空航天等相关专业学生的参考书。

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